





## SID4 UV

## COST-EFFECTIVE, HIGH RESOLUTION UV WAVEFRONT SENSOR

Bringing high-resolution wavefront sensing as low as 250 nm, SID4 UV is perfectly suited for UV optics testing, UV laser characterization (used in lithography or semiconductor applications) and surface inspection of lenses and wafers.

APPLICATIONS: Laser industry | Semiconductor | Astronomy | Aerospace | AR/VR

SPECIFICATIONS	
Wavelength range	250 - 400 nm
Aperture dimensions	7.4 x 7.4 mm <sup>2</sup>
Phase spatial resolution	29.6 μm
Phase & Intensity sampling	250 x 250
Resolution (Phase)	2 nm RMS
Accuracy (Absolute)	10 nm RMS
Frame rate	> 30 fps
Real-time processing frequency	2 fps (full resolution)*
Interface	Giga Ethernet
Dimensions	45 x 30 x 100 mm <sup>3</sup>
Weight	~ 250g

\* with SID4 software

